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|  |                 | M-10685-1P US   | 09/778,245           |                |          |                            |    |
| INFORMATION DISCLOSURE STATEMENT BY APPLICANT<br><i>TYPE</i><br><i>(See several sheets if necessary)</i>   |                 | Applicant(s)  |                      |                |          |                            |    |
|  |                 | SHING LEE ET AL.  |                      |                |          |                            |    |
|  |                 | Filing Date   | Group                |                |          |                            |    |
|  |                 | February 6, 2001  | 2877                 |                |          |                            |    |
| U.S. Patent Documents  |                 |   |                      |                |          |                            |    |
| *Examiner Initial  | Document Number | Date  | Name                 | Class          | Subclass | Filing Date If Appropriate |    |
| HP   | AA 5,042,951    | 8/91  | Gold et al.          |                |          |                            |    |
| HP   | AB 5,166,752    | 11/92   | Spanier et al.       |                |          |                            |    |
| HP   | AC 5,181,080    | 1/93  | Fantom et al.        |                |          |                            |    |
| HP   | AD 5,486,701    | 1/96  | Norton et al.        |                |          |                            |    |
| HP   | AE 5,596,406    | 1/97  | Rosencwaig et al.    |                |          |                            |    |
| HP   | AF 5,608,526    | 3/97  | Piwonka-Corle et al. |                |          |                            |    |
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| Foreign Patent Documents   |                 |   |                      | Translation    |          |                            |    |
|  | Document        | Date  | Country              | Class          | Subclass | Yes                        | No |
| OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)   |                 |   |                      |                |          |                            |    |
| HP   | AI              | "Analysis of Semiconductor Surfaces With Very Thin Native Oxide Layers By Combined Immersion And Multiple Angle Of Incidence Ellipsometry," I. Ohlidal et al., <i>Applied Surface Science</i> , 35 (1988-89), pp. 259-273                         |                      |                |          |                            |    |
| HP   | AJ              | "Determination of the "Optical" Thickness And Of The Filling Factor Of Discontinuous Au Films From Photometric And Ellipsometric Measurements," E. Elizalde et al., <i>Optics Communications</i> , Vol. 60, No. 6, December 15, 1986, pp. 378-382 |                      |                |          |                            |    |
| HP   | AK              | "Variable Angle Spectroscopic Ellipsometry," S.A. Alterovitz et al., <i>Solid State Technology</i> , March 1988   |                      |                |          |                            |    |
| HP   | AL              | "Application of spectroscopic ellipsometry to complex samples," J.L. Freeouf, <i>Appl. Phys. Lett.</i> , 53(24), December 12, 1988, pp. 2426-2428   |                      |                |          |                            |    |
| HP   | AM              | "Spectroscopic ellipsometry studies of SIMOX structures and correlation with cross-section TEM," <i>Vacuum</i> , Vol. 42, Nos. 5/6, 1991, pp. 359-365   |                      |                |          |                            |    |
| HP   | AN              | "Spectroscopic Ellipsometry for the Characterization of Thin Films," F. Ferrieu et al. <i>J. Electrochem. Soc.</i> , 137, No. 7, July 1990, pp. 2203-2208   |                      |                |          |                            |    |
| HP   | AO              | International Search Report dated 6/8/2000  |                      |                |          |                            |    |
| Examiner   | <i>HP Raw</i>   | Date Considered   |                      | <i>1/23/02</i> |          |                            |    |
| *EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant. |                 |   |                      |                |          |                            |    |